Abstracts

Large signal bias-dependent modeling of PHEMTs by pulsed measurements

B.L. Ooi, K. Lan, M.S. Leong and K.S. Kooi. "Large signal bias-dependent modeling of PHEMTs by pulsed measurements." 2001 Radio Frequency Integrated Circuits (RFIC) Symposium 01. (2001 [RFIC]): 155-157.

A bias-dependent large signal model and corresponding parameter extraction procedures are presented to characterize PHEMT devices by pulsed measurements. Two nonlinear current sources and few additional parameters are used to model bias-dependence of the drain current. Results show that the method discussed in this paper can be applied to model the large signal behavior of PHEMTs from DC to RF at any bias points.

❑ Return to main document.